



Reliability Data Report

Product Family R541

LT3650 / LT3651 / LT3652

Reliability Data Report

Report Number: R541

Report generated on: Wed Oct 31 14:11:05 PDT 2012

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) ¹	No. of FAILURES ^{2, 3}
QFN/DFN	308	0826	1005	269	0
Totals	308	-	-	269	0
PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SOIC/SOT/MSOP	98	0937	1005	4	0
QFN/DFN	296	0912	1033	30	0
Totals	394	-	-	34	0
TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	196	0914	1033	19	0
SOIC/SOT/MSOP	50	1005	1005	5	0
Totals	246	-	-	24	0
THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SOIC/SOT/MSOP	100	0937	1005	10	0
QFN/DFN	577	0912	1033	325	0
Totals	677	-	-	335	0
<p>(1) Assumes Activation Energy = 1.0 Electron Volts</p> <p>(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =6.81 FITS</p> <p>(3) Mean Time Between Failure in Years = 16750.93</p> <p>Note: 1 FIT = 1 Failure in One Billion Hours.</p> <p>Note 2: HAST, PCT, Temp Cycle & Thermal Shock are subjected to J-STD-020 Preconditioning</p>					